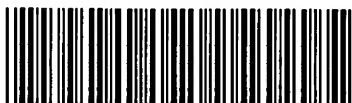


**Search Notes**

Application/Control No.

10/623,155

Examiner

Shin-Lin Chen

Applicant(s)/Patent under  
Reexamination

WANG ET AL.

Art Unit

1632

**SEARCHED**

Class	Subclass	Date	Examiner
536	23.1		
536	23.5		
435	320.1		
424	93.2		
435	455		
424	184.1	11/6/2006	<i>SL</i>

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
424	184.1		
536	23.5		
435	320.1		
435/455, 424/93.2, sequence interference search		11/6/2006	<i>SL</i>

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated, parents reviewed and updated, inventor name search.	11/6/2006	<i>SL</i>